







SN74AXC4T774 SCES898C - JULY 2019 - REVISED MAY 2022

SN74AXC4T774 4-Bit Dual-Supply Bus Transceiver with Independent Direction Control, Configurable Voltage Translation, and Tri-State Outputs

1 Features

- Fully configurable dual-rail design allows each port to operate with a power supply range from 0.65 V to 3.6 V
- Operating temperature from -40°C to +125°C
- Independent direction control pins to allow configurable up and down translation
- Glitch-free power supply sequencing
- Up to 310 Mbps support when translating from 1.8 V to 3.3 V
- V_{CC} isolation feature
 - If either V_{CC} input is below 100 mV, all I/Os outputs are disabled and become highimpedance
- I_{off} supports partial-power-down mode operation
- Compatible with AVC family level shifters
- Latch-up performance exceeds 100 mA per JESD 78. Class II
- ESD protection exceeds JESD 22
 - 8000-V human-body model
 - 1000-V charged-device model

2 Applications

- Enterprise and communications
- Industrial
- Personal electronics
- Wireless infrastructure
- **Building automation**
- Point of sale

3 Description

The SN74AXC4T774 is a four-bit non-inverting bus transceiver that uses two individually configurable power-supply rails. The device is operational with both V_{CCA} and V_{CCB} supplies as low as 0.65 V. The A port is designed to track V_{CCA}, which accepts any supply voltage from 0.65 V to 3.6 V. The B port is designed to track V_{CCB}, which also accepts any supply voltage from 0.65 V to 3.6 V. Additionally the SN74AXC4T774 is compatible with a single-supply system.

SN74AXC4T774 The device is designed for asynchronous communication between data buses. The device transmits data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level of the direction-control inputs (DIRx). The output-enable input (OE) is used to disable the outputs so the buses are effectively isolated. The SN74AXC4T774 device is designed so the control pins (DIRx and \overline{OE}) are referenced to V_{CCA} .

To put the level shifter I/Os in the high-impedance state during power up or power down, tie the \overline{OE} pin to V_{CCA} through a pullup resistor.

This device is fully specified for partial-power-down applications using the I_{off} current. The I_{off} protection circuitry is designed so that no excessive current is drawn from or to an input, output, or combined I/O that is biased to a specific voltage while the device is powered down.

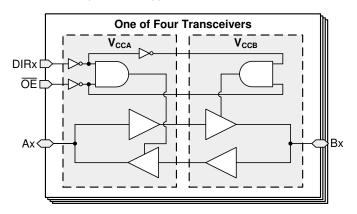
The V_{CC} isolation feature is designed so that if either V_{CCA} or V_{CCB} is less than 100 mV, both I/O ports are set to the high-impedance state by disabling their outputs.

Glitch-free power supply sequencing allows either supply rail to be powered on or off in any order while providing robust power sequencing performance.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾
	PW (TSSOP, 16)	5mm × 6.4mm
SN74AXC4T774	BQB (WQFN, 16)	3.5mm × 2.5mm
	RSV (UQFN ,16)	2.6mm × 1.8mm

- For more information, see Section 11
- The package size (length × width) is a nominal value and includes pins, where applicable.



Functional Block Diagram

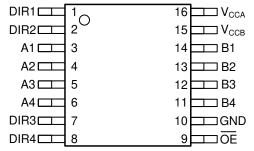


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4 Pin Configuration and Functions



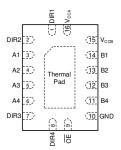


Figure 4-1. PW Package, 16-Pin TSSOP (Top View)

Figure 4-2. BQB Package, 16-Pin WQFN (Transparent Top View)

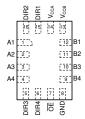


Figure 4-3. RSV Package, 16-Pin UQFN (Transparent Top View)

Tabl	1_4 ما	Pin	Fun	ctions
ıav	IC 4-I	I. FIII	ı uıı	CHUHS

	PIN				
NAME	PW	RSV	BQB	TYPE ⁽¹⁾	DESCRIPTION
A1	3	1	3	I/O	Input/output A1. Referenced to V _{CCA} .
A2	4	2	4	I/O	Input/output A2. Referenced to V _{CCA} .
A3	5	3	5	I/O	Input/output A3. Referenced to V _{CCA} .
A4	6	4	6	I/O	Input/output A4. Referenced to V _{CCA} .
B1	14	12	14	I/O	Input/output B1. Referenced to V _{CCB} .
B2	13	11	13	I/O	Input/output B2. Referenced to V _{CCB} .
В3	12	10	12	I/O	Input/output B3. Referenced to V _{CCB} .
B4	11	9	11	I/O	Input/output B4. Referenced to V _{CCB} .
DIR1	1	15	1	1	Direction-control input for port 1. Referenced to V _{CCA} .
DIR2	2	16	2	1	Direction-control input for port 2. Referenced to V _{CCA} .
DIR3	7	5	7	1	Direction-control input for port 3. Referenced to V _{CCA} .
DIR4	8	6	8	1	Direction-control input for port 4. Referenced to V _{CCA} .
ŌĒ	9	7	9	I	Tri-state output enable. Pull $\overline{\text{OE}}$ high to place all outputs in tri-state mode. Referenced to V_{CCA} .
GND	10	8	10	_	Ground
V _{CCA}	16	14	16	_	A-port power supply voltage. 0.65 V ≤ V _{CCA} ≤ 3.6 V
V _{CCB}	15	13	15	_	B-port power supply voltage. 0.65 V ≤ V _{CCB} ≤ 3.6 V

(1) I = input, O = output



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CCA}	Supply voltage A		-0.5	4.2	V
V _{CCB}	Supply voltage B		-0.5	4.2	V
		I/O Ports (A Port)	-0.5	4.2	
V_{I}	Input Voltage ⁽²⁾	I/O Ports (B Port)	-0.5	4.2	V
		Control Inputs	-0.5	4.2	
\ /	Valance and led to any output in the bight insured and a group off state (2)	A Port	-0.5	4.2	V
Vo	Voltage applied to any output in the high-impedance or power-off state ⁽²⁾	B Port	-0.5	4.2	V
.,	Value as a subject to a supplied to a supplied to a big to a big to a large state (2) (3)	A Port	-0.5	V _{CCA} + 0.2	V
Vo	Voltage applied to any output in the high or low state ^{(2) (3)}	B Port	-0.5	V _{CCB} + 0.2	V
I _{IK}	Input clamp current	V _I < 0	-50		mA
I _{OK}	Output clamp current	V _O < 0	-50		mA
Io	Continuous output current		-50	50	mA
	Continuous current through V _{CC} or GND		-100	100	mA
Tj	Junction Temperature			150	°C
T _{stg}	Storage temperature		-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- (2) The input voltage and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.
- (3) The output positive-voltage rating may be exceeded up to 4.2 V maximum if the output current rating is observed.

5.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±8000	V
V _(ESD)	Liectiostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±1000	v

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1) 2

	-			MIN	MAX	UNIT
V _{CCA}	Supply voltage A			0.65	3.6	V
V _{CCB}	Supply voltage B			0.65	3.6	V
			V _{CCI} = 0.65 V - 0.75 V	V _{CCI} x 0.70		
			V _{CCI} = 0.76 V - 1 V	V _{CCI} x 0.70		
		Data Inputs	V _{CCI} = 1.1 V - 1.95 V	V _{CCI} x 0.65		
			V _{CCI} = 2.3 V - 2.7 V	1.6		
			V _{CCI} = 3 V - 3.6 V	2		
V _{IH}	High-level input voltage		V _{CCA} = 0.65 V - 0.75 V	V _{CCA} x 0.70		
			V _{CCA} = 0.76 V - 1 V	V _{CCA} x 0.70		
		Control Inputs(DIRx, OE), Referenced to V _{CCA}	V _{CCA} = 1.1 V - 1.95 V	V _{CCA} x 0.65		
		OE), referenced to VCCA	V _{CCA} = 2.3 V - 2.7 V	1.6		
			V _{CCA} = 3 V - 3.6 V	2		
			V _{CCI} = 0.65 V - 0.75 V		V _{CCI} x 0.30	
			V _{CCI} = 0.76 V - 1 V		V _{CCI} x 0.30	
		Data Inputs	V _{CCI} = 1.1 V - 1.95 V		V _{CCI} x 0.35	
			V _{CCI} = 2.3 V - 2.7 V		0.7	
. ,			V _{CCI} = 3 V - 3.6 V		0.8	.,
V _{IL}	Low-level input voltage		V _{CCA} = 0.65 V - 0.75 V		V _{CCA} x 0.30	V
			V _{CCA} = 0.76 V - 1 V		V _{CCA} x 0.30	
		Control Inputs(DIRx, OE), Referenced to V _{CCA}	V _{CCA} = 1.1 V - 1.95 V		V _{CCA} x 0.35	
		OE), referenced to VCCA	V _{CCA} = 2.3 V - 2.7 V		0.7	
			V _{CCA} = 3 V - 3.6 V		0.8	
V _I	Input voltage 1		,	0	3.6	V
.,	0	Active State		0	V _{cco}	
Vo	Output voltage	Tri-State		0	3.6	V
Δt/Δv ²	Input transition rise and fal	I time			10	ns/V
T _A	Operating free-air tempera	ture		-40	125	°C

5.4 Thermal Information

			SN74AXC4T774		
	THERMAL METRIC(1)	PW (TSSOP)	RSV (UQFN)	BQB (WQFN)	UNIT
		16 PINS	16 PINS	16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	118.2	130.8	73.7	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	48.6	69.1	70.9	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	64.5	59.9	43.5	°C/W
Y _{JT}	Junction-to-top characterization parameter	7.3	3.9	4.9	°C/W
Y_{JB}	Junction-to-board characterization parameter	63.9	58.3	43.5	°C/W
R _{θJC(bottom)}	Junction-to-case (bottom) thermal resistance	NA	NA	21.2	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

 V_{CCI} is the V_{CC} associated with the input port. V_{CCO} is the V_{CC} associated with the output port. All unused inputs of the device must be held at V_{CC} or GND for proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, SCBA004.



5.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted) (1) (2)

							Operating	g free-aiı	tempera	ture (T _A)		
P	ARAMETER	TEST	CONDITIONS	V _{CCA}	V _{CCB}	-40)°C to 85°	,C	-40	°C to 125°	С	UNIT
						MIN	TYP ⁽⁴⁾	MAX	MIN	TYP ⁽⁴⁾	MAX	
			I _{OH} = -100 μA	0.7 V - 3.6 V	0.7 V - 3.6 V	V _{CCO} - 0.1			V _{CCO} – 0.1			
			I _{OH} = -50 μA	0.65 V	0.65 V	0.55			0.55			
			I _{OH} = -200 μA	0.76 V	0.76 V	0.58			0.58			
	High-level output		I _{OH} = -500 μA	0.85 V	0.85 V	0.65			0.65			
/ _{OH}	voltage	$V_I = V_{IH}$	I _{OH} = -3 mA	1.1 V	1.1 V	0.85			0.85			V
			I _{OH} = -6 mA	1.4 V	1.4 V	1.05			1.05			
			I _{OH} = -8 mA	1.65 V	1.65 V	1.2			1.2			
			I _{OH} = -9 mA	2.3 V	2.3 V	1.75			1.75			
			I _{OH} = -12 mA	3 V	3 V	2.3			2.3			
			I _{OL} = 100 μA	0.7 V - 3.6 V	0.7 V - 3.6 V			0.1			0.1	
			I _{OL} = 50 μA	0.65 V	0.65 V			0.1			0.1	
			I _{OL} = 200 μA	0.76 V	0.76 V			0.18			0.18	
			I _{OL} = 500 μA	0.85 V	0.85 V			0.2			0.2	
o _L	Low-level output voltage	$V_I = V_{IL}$	I _{OL} = 3 mA	1.1 V	1.1 V			0.25			0.25	V
	Voltage		I _{OL} = 6 mA	1.4 V	1.4 V			0.35			0.35	
			I _{OL} = 8 mA	1.65 V	1.65 V			0.45			0.45	
			I _{OL} = 9 mA	2.3 V	2.3 V			0.55			0.55	
			I _{OL} = 12 mA	3 V	3 V			0.7			0.7	
	Input leakage	Control inp	outs (DIRx, OE):V _I =	0.65 V- 3.6 V	0.65 V- 3.6 V	-0.5		0.5	-1		1	μΑ
I	current	Data Input or GND	ts $(Ax, Bx), V_I = V_{CCI}$	0.65 V- 3.6 V	0.65 V- 3.6 V	-4		4	-8		8	μA
	Partial power	A Port: V _I	or V _O = 0 V - 3.6 V	0 V	0 V - 3.6 V	-4		4	-8		8	
off	down current	B Port: V _I	or V _O = 0 V - 3.6 V	0 V - 3.6 V	0 V	-4		4	-8		8	μA
OZ	Tri-state output current (3)		t, $V_I = V_{CCI}$ or GND, or GND, $\overline{OE} = V_{IH}$	3.6 V	3.6 V	-4		4	-8		8	μA
				0.65 V- 3.6 V	0.65 V- 3.6 V			15			27	
CCA	V _{CCA} supply current	V _I = V _{CCI} or GND	I _O = 0	0 V	3.6 V	-2			-12			μΑ
		0.12		3.6 V	0 V			10			18	
				0.65 V- 3.6 V	0.65 V- 3.6 V			15			27	
ССВ	V _{CCB} supply current	V _I = V _{CCI} or GND	I _O = 0	0 V	3.6 V			10			18	μΑ
	Current	OI OIVD		3.6 V	0 V	-2			-12			
CCA +	Combined supply current	V _I = V _{CCI} or GND	I _O = 0	0.65 V- 3.6 V	0.65 V- 3.6 V			21			40	μA
ì	Control Input Capacitance	V _I = 3.3 V	or GND	3.3 V	3.3 V		4.5			4.5		pF
C _{io}	Data I/O Capacitance		A, V _O = 1.65V DC +1 Bm sine wave	3.3 V	3.3 V		6.5			6.5		pF

V_{CCI} is the V_{CC} associated with the input port.
 V_{CCO} is the V_{CC} associated with the output port.
 For I/O ports, the parameter I_{OZ} includes the input leakage current.
 All typical data is taken at 25°C.



5.6 Switching Characteristics, $V_{CCA} = 0.7 \pm 0.05 \text{ V}$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V _{CCB})														
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05 V	0.8 ± 0	.04 V	0.9 ± 0.	045 V	1.2 ± ().1 V	1.5 ± ().1 V	1.8 ± 0	.15 V	2.5 ± 0).2 V	3.3 ± 0).3 V	UNIT							
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX								
		_	В	-40°C to 85°C	0.5	172	0.5	120	0.5	88	0.5	51	0.5	46	0.5	56	0.5	78	0.5	221								
	Propagation	A	В	-40°C to 125°C	0.5	172	0.5	120	0.5	88	0.5	51	0.5	46	0.5	56	0.5	78	0.5	221	ns							
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	172	0.5	141	0.5	109	0.5	51	0.5	16	0.5	12	0.5	9	0.5	9	115							
		D	^	-40°C to 125°C	0.5	172	0.5	141	0.5	109	0.5	51	0.5	16	0.5	12	0.5	9	0.5	9								
		ŌĒ	Α	-40°C to 85°C	0.5	205	0.5	205	0.5	205	0.5	205	0.5	205	0.5	205	0.5	205	0.5	205								
	Disable time	OE	A	-40°C to 125°C	0.5	205	0.5	205	0.5	205	0.5	205	0.5	205	0.5	205	0.5	205	0.5	205	ns							
t _{dis}	Disable time	ŌĒ	ŌĒ	OF.	OE	В	-40°C to 85°C	0.5	189	0.5	161	0.5	145	0.5	102	0.5	99	0.5	102	0.5	113	0.5	176					
					-40°C to 125°C	0.5	189	0.5	161	0.5	145	0.5	102	0.5	99	0.5	102	0.5	113	0.5	176							
			OE .		<u> </u>	0	OF.	OF	<u> </u>	OF A	Α	-40°C to 85°C	0.5	287	0.5	287	0.5	287	0.5	287	0.5	287	0.5	287	0.5	287	0.5	287
	Enable time	OE	A	-40°C to 125°C	0.5	287	0.5	287	0.5	287	0.5	287	0.5	287	0.5	287	0.5	287	0.5	287	no							
t _{en}			ŌĒ	ŌĒ		OF I	OF (<u>of</u> ,		-40°C to 85°C	0.5	309	0.5	219	0.5	177	0.5	133	0.5	127	0.5	132	0.5	165	0.5	418	ns	
						-40°C to 125°C	0.5	309	0.5	219	0.5	177	0.5	133	0.5	127	0.5	132	0.5	165	0.5	418						

Submit Document Feedback



5.7 Switching Characteristics, $V_{CCA} = 0.8 \pm 0.04 \text{ V}$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V _{CCB})												
P.	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05 V	0.8 ± 0	.04 V	0.9 ± 0.	045 V	1.2 ± ().1 V	1.5 ± ().1 V	1.8 ± 0	.15 V	2.5 ± ().2 V	3.3 ± 0).3 V	UNIT					
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX						
		Α	В	-40°C to 85°C	0.5	141	0.5	96	0.5	73	0.5	39	0.5	29	0.5	28	0.5	29	0.5	40						
	Propagation			-40°C to 125°C	0.5	141	0.5	96	0.5	73	0.5	39	0.5	29	0.5	28	0.5	29	0.5	40	ns					
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	120	0.5	96	0.5	76	0.5	39	0.5	16	0.5	11	0.5	9	0.5	9	115					
		В	^	-40°C to 125°C	0.5	120	0.5	96	0.5	76	0.5	39	0.5	16	0.5	12	0.5	9	0.5	9						
	Ī	OE B	ŌĒ	^	-40°C to 85°C	0.5	114	0.5	114	0.5	114	0.5	114	0.5	114	0.5	114	0.5	114	0.5	114					
t _{dis}	Disable time		^	-40°C to 125°C	0.5	114	0.5	114	0.5	114	0.5	114	0.5	114	0.5	114	0.5	114	0.5	114	ns					
^L dis	Disable time		OF.	ŌĒ	ŌĒ	ŌĒ	ŌĒ B	R	-40°C to 85°C	0.5	156	0.5	131	0.5	116	0.5	71	0.5	67	0.5	68	0.5	70	0.5	84	115
			ŌĒ	ŌĒ	OE	Ь	-40°C to 125°C	0.5	156	0.5	131	0.5	116	0.5	71	0.5	67	0.5	68	0.5	70	0.5	84			
			ŌĒ A	ŌĒ A	ŌĒ A	^	-40°C to 85°C	0.5	161	0.5	161	0.5	161	0.5	161	0.5	161	0.5	161	0.5	161	0.5	161			
	Enable time					ŌĒ	DE ,	DE ,	DE A	ŌĒ A	OE A	-40°C to 125°C	0.5	161	0.5	161	0.5	161	0.5	161	0.5	161	0.5	161	0.5	161
t _{en}		ŌĒ		В	-40°C to 85°C	0.5	258	0.5	174	0.5	137	0.5	90	0.5	73	0.5	71	0.5	77	0.5	106	ns				
			D	-40°C to 125°C	0.5	258	0.5	174	0.5	137	0.5	90	0.5	73	0.5	71	0.5	77	0.5	106						



5.8 Switching Characteristics, $V_{CCA} = 0.9 \pm 0.045 V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V _{CCB})																	
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05 V	0.8 ± 0	.04 V	0.9 ± 0.	045 V	1.2 ± ().1 V	1.5 ± ().1 V	1.8 ± 0	.15 V	2.5 ± 0).2 V	3.3 ± ().3 V	UNIT										
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX											
		Α	В	-40°C to 85°C	0.5	109	0.5	76	0.5	60	0.5	33	0.5	23	0.5	21	0.5	21	0.5	24											
	Propagation			-40°C to 125°C	0.5	109	0.5	76	0.5	60	0.5	33	0.5	23	0.5	21	0.5	21	0.5	24	ns										
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	88	0.5	73	0.5	60	0.5	33	0.5	16	0.5	11	0.5	9	0.5	9	115										
		B		-40°C to 125°C	0.5	88	0.5	73	0.5	60	0.5	33	0.5	16	0.5	12	0.5	9	0.5	9											
	<u></u>	ŌĒ	Α	-40°C to 85°C	0.5	83	0.5	83	0.5	83	0.5	83	0.5	83	0.5	83	0.5	83	0.5	83											
t _{dis}	Disable time	OL		-40°C to 125°C	0.5	83	0.5	83	0.5	83	0.5	83	0.5	83	0.5	83	0.5	83	0.5	83	ns										
^L dis	Disable time	OF.	OF.	OE .	ŌĒ	OE	В	-40°C to 85°C	0.5	138	0.5	112	0.5	97	0.5	51	0.5	46	0.5	46	0.5	46	0.5	54	115						
		ŌĒ	ŌĒ	OE	Ь	-40°C to 125°C	0.5	138	0.5	112	0.5	97	0.5	51	0.5	46	0.5	46	0.5	46	0.5	54									
		OF.	ŌĒ ,	ŌĒ ,	ŌĒ ,	ŌĒ ,	ŌĒ A	ŌĒ A	ŌĒ A	ŌĒ A	OE .	OF A		-40°C to 85°C	0.5	94	0.5	94	0.5	94	0.5	94	0.5	94	0.5	94	0.5	94	0.5	94	
	Enable time	ŌĒ									-40°C to 125°C	0.5	94	0.5	94	0.5	94	0.5	94	0.5	94	0.5	94	0.5	94	0.5	94	no			
t _{en}				OF P	ŌĒ B		-40°C to 85°C	0.5	203	0.5	140	0.5	110	0.5	70	0.5	52	0.5	45	0.5	43	0.5	51	ns							
				В	-40°C to 125°C	0.5	203	0.5	140	0.5	110	0.5	74	0.5	54	0.5	47	0.5	43	0.5	51										

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5.9 Switching Characteristics, $V_{CCA} = 1.2 \pm 0.1 \text{ V}$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V _{CCB})							
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05 V	0.8 ± 0	.04 V	0.9 ± 0.	045 V	1.2 ± ().1 V	1.5 ± ().1 V	1.8 ± 0	.15 V	2.5 ± ().2 V	3.3 ± ().3 V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	50	0.5	39	0.5	33	0.5	20	0.5	14	0.5	12	0.5	10	0.5	12	
	Propagation			-40°C to 125°C	0.5	50	0.5	39	0.5	33	0.5	20	0.5	14	0.5	12	0.5	10	0.5	12	ns
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	51	0.5	39	0.5	33	0.5	20	0.5	15	0.5	11	0.5	8	0.5	7	115
				-40°C to 125°C	0.5	51	0.5	39	0.5	33	0.5	20	0.5	15	0.5	12	0.5	8	0.5	7	
		ŌĒ	Α	-40°C to 85°C	0.5	28	0.5	28	0.5	28	0.5	28	0.5	28	0.5	28	0.5	28	0.5	28	
t _{dis}	Disable time	OL		-40°C to 125°C	0.5	29	0.5	29	0.5	29	0.5	29	0.5	29	0.5	29	0.5	29	0.5	29	ns
^L dis	Disable time	ŌĒ	В	-40°C to 85°C	0.5	123	0.5	95	0.5	78	0.5	33	0.5	26	0.5	25	0.5	23	0.5	26	
		OL	Ь	-40°C to 125°C	0.5	124	0.5	95	0.5	79	0.5	34	0.5	27	0.5	26	0.5	24	0.5	26	
		ŌĒ	Α	-40°C to 85°C	0.5	39	0.5	39	0.5	39	0.5	39	0.5	39	0.5	39	0.5	39	0.5	39	
	Enable time	OE	A	-40°C to 125°C	0.5	40	0.5	40	0.5	40	0.5	40	0.5	40	0.5	40	0.5	40	0.5	40	I I
t _{en}	LIIADIE IIIIE	ŌĒ	В	-40°C to 85°C	0.5	124	0.5	87	0.5	70	0.5	51	0.5	38	0.5	33	0.5	26	0.5	25	ns
		OL	В	-40°C to 125°C	0.5	124	0.5	87	0.5	70	0.5	55	0.5	42	0.5	36	0.5	28	0.5	26	

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5.10 Switching Characteristics, $V_{CCA} = 1.5 \pm 0.1 \text{ V}$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V _{CCB})							
P.	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05 V	0.8 ± 0	.04 V	0.9 ± 0.	045 V	1.2 ± (0.1 V	1.5 ± ().1 V	1.8 ± 0	.15 V	2.5 ± (0.2 V	3.3 ± 0).3 V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	16	0.5	16	0.5	16	0.5	15	0.5	11	0.5	10	0.5	8	0.5	10	
	Propagation			-40°C to 125°C	0.5	16	0.5	16	0.5	16	0.5	15	0.5	11	0.5	10	0.5	8	0.5	10	ns
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	47	0.5	29	0.5	23	0.5	14	0.5	11	0.5	9	0.5	7	0.5	6	115
			^	-40°C to 125°C	0.5	47	0.5	29	0.5	23	0.5	14	0.5	11	0.5	9	0.5	7	0.5	6	
		ŌĒ	Α	-40°C to 85°C	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	
t _{dis}	Disable time	OL	^	-40°C to 125°C	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	ns
^L dis	Disable time	ŌĒ	В	-40°C to 85°C	0.5	120	0.5	91	0.5	74	0.5	29	0.5	22	0.5	20	0.5	20	0.5	20	
		OL	Ь	-40°C to 125°C	0.5	120	0.5	92	0.5	75	0.5	30	0.5	23	0.5	22	0.5	19	0.5	20	
		ŌĒ	Α	-40°C to 85°C	0.5	24	0.5	24	0.5	24	0.5	24	0.5	24	0.5	24	0.5	24	0.5	24	
	Enable time	OE	A	-40°C to 125°C	0.5	25	0.5	25	0.5	25	0.5	25	0.5	25	0.5	25	0.5	25	0.5	25	
t _{en}	LIIADIE IIIIE	ŌĒ	В	-40°C to 85°C	0.5	28	0.5	29	0.5	33	0.5	41	0.5	31	0.5	27	0.5	22	0.5	19	ns
		OL .	D	-40°C to 125°C	0.5	29	0.5	30	0.5	33	0.5	42	0.5	33	0.5	29	0.5	24	0.5	21	

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5.11 Switching Characteristics, $V_{CCA} = 1.8 \pm 0.15 \text{ V}$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V _{CCB})							
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05 V	0.8 ± 0	.04 V	0.9 ± 0.	045 V	1.2 ± ().1 V	1.5 ± ().1 V	1.8 ± 0	.15 V	2.5 ± ().2 V	3.3 ± ().3 V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	12	0.5	11	0.5	11	0.5	11	0.5	9	0.5	8	0.5	7	0.5	7	
	Propagation			-40°C to 125°C	0.5	12	0.5	12	0.5	12	0.5	12	0.5	9	0.5	9	0.5	7	0.5	7	ne
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	56	0.5	28	0.5	21	0.5	12	0.5	10	0.5	8	0.5	6	0.5	5	ns
			^	-40°C to 125°C	0.5	56	0.5	28	0.5	21	0.5	12	0.5	10	0.5	9	0.5	7	0.5	6	
		ŌĒ	Α	-40°C to 85°C	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	
t _{dis}	Disable time	OL	^	-40°C to 125°C	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	ns
^L dis	Disable time	ŌĒ	В	-40°C to 85°C	0.5	117	0.5	90	0.5	73	0.5	28	0.5	21	0.5	19	0.5	16	0.5	18	
		OL	Ь	-40°C to 125°C	0.5	119	0.5	90	0.5	74	0.5	29	0.5	22	0.5	20	0.5	17	0.5	18	
		ŌĒ	Α	-40°C to 85°C	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	
	Enable time	OE	A	-40°C to 125°C	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	0.5	20	I I
t _{en}	LIIADIE IIIIE	ŌĒ	В	-40°C to 85°C	0.5	21	0.5	20	0.5	20	0.5	32	0.5	27	0.5	24	0.5	20	0.5	18	ns
		OL	D	-40°C to 125°C	0.5	22	0.5	22	0.5	22	0.5	34	0.5	29	0.5	26	0.5	22	0.5	19	



5.12 Switching Characteristics, $V_{CCA} = 2.5 \pm 0.2 \text{ V}$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V _{CCB})							
P	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05 V	0.8 ± 0	.04 V	0.9 ± 0.	045 V	1.2 ± ().1 V	1.5 ± ().1 V	1.8 ± 0	.15 V	2.5 ± ().2 V	3.3 ± ().3 V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		_	В	-40°C to 85°C	0.5	10	0.5	10	0.5	9	0.5	8	0.5	7	0.5	6	0.5	6	0.5	6	
	Propagation	A	В	-40°C to 125°C	0.5	10	0.5	10	0.5	9	0.5	8	0.5	7	0.5	7	0.5	6	0.5	6	ns
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	78	0.5	30	0.5	21	0.5	10	0.5	8	0.5	7	0.5	6	0.5	5	115
			^	-40°C to 125°C	0.5	78	0.5	30	0.5	21	0.5	10	0.5	8	0.5	7	0.5	6	0.5	5	
		ŌĒ	Α	-40°C to 85°C	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	
	Disable time	OE	A	-40°C to 125°C	0.5	14	0.5	14	0.5	14	0.5	14	0.5	14	0.5	14	0.5	14	0.5	14	ns
t _{dis}	Disable time	ŌĒ	В	-40°C to 85°C	0.5	115	0.5	89	0.5	72	0.5	26	0.5	19	0.5	18	0.5	14	0.5	17	115
				-40°C to 125°C	0.5	117	0.5	89	0.5	72	0.5	28	0.5	21	0.5	19	0.5	15	0.5	17	
		ŌĒ	Α	-40°C to 85°C	0.5	14	0.5	14	0.5	14	0.5	14	0.5	14	0.5	14	0.5	14	0.5	14	
	Enable time	OL	^	-40°C to 125°C	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	
t _{en}	LITADIE UITIE	ŌĒ	В	-40°C to 85°C	0.5	15	0.5	14	0.5	13	0.5	14	0.5	15	0.5	16	0.5	15	0.5	15	ns
				-40°C to 125°C	0.5	16	0.5	15	0.5	15	0.5	16	0.5	17	0.5	18	0.5	17	0.5	16	

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5.13 Switching Characteristics, $V_{CCA} = 3.3 \pm 0.3 V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

	DADAMETED										B-Port S	Supply	Voltage	(V _{CCB})							
	PARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05 V	0.8 ± 0	.04 V	0.9 ± 0.	045 V	1.2 ± (0.1 V	1.5 ± (0.1 V	1.8 ± 0	.15 V	2.5 ±	0.2 V	3.3 ± ().3 V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	10	0.5	9	0.5	9	0.5	8	0.5	6	0.5	6	0.5	5	0.5	5	
	Propagation			-40°C to 125°C	0.5	10	0.5	9	0.5	9	0.5	8	0.5	6	0.5	6	0.5	5	0.5	5	ne
t _{pd}	delay	В	Α	-40°C to 85°C	0.5	221	0.5	40	0.5	24	0.5	12	0.5	10	0.5	7	0.5	6	0.5	5	ns
			^	-40°C to 125°C	0.5	221	0.5	40	0.5	24	0.5	12	0.5	10	0.5	7	0.5	6	0.5	5	
		ŌĒ	Α	-40°C to 85°C	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	
t _{dis}	Disable time	OL	^	-40°C to 125°C	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	ns
^L dis	Disable time	ŌĒ	В	-40°C to 85°C	0.5	115	0.5	89	0.5	72	0.5	26	0.5	19	0.5	17	0.5	14	0.5	16	115
		OL		-40°C to 125°C	0.5	117	0.5	89	0.5	72	0.5	27	0.5	20	0.5	18	0.5	14	0.5	16	
		ŌĒ	Α	-40°C to 85°C	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	
	Enable time	OE	^	-40°C to 125°C	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	0.5	13	
t _{en}	Lilable tille	ŌĒ	В	-40°C to 85°C	0.5	13	0.5	12	0.5	11	0.5	11	0.5	11	0.5	12	0.5	12	0.5	12	ns
		OE	<u> </u>	-40°C to 125°C	0.5	14	0.5	12	0.5	12	0.5	12	0.5	12	0.5	13	0.5	13	0.5	13	



5.14 Operating Characteristics: $T_A = 25$ °C

	PARAMETER	TEST CONDITIONS	V _{CCA}	V _{CCB}	MIN	TYP	MAX	UNIT
			0.7 V	0.7 V		2.4		
			0.8 V	0.8 V		2.3		
			0.9 V	0.9 V		2.2		
	Power Dissipation Capacitance	$C_L = 0$, $R_L = Open$	1.2 V	1.2 V		2.2		
	per transceiver (A to B: outputs enabled)	f = 1 MHz t _{rise} = t _{fall} = 1 ns	1.5 V	1.5 V		2.2		pF
			1.8 V	1.8 V		2.2		
			2.5 V	2.5 V		2.4		
			3.3 V	3.3 V		3.0		
			0.7 V	0.7 V		1.5		
			0.8 V	0.8 V		1.5		
			0.9 V	0.9 V		1.5		
	Power Dissipation Capacitance	$C_L = 0$, $R_L = Open$ f = 1 MHz	1.2 V	1.2 V	1.5 1.5 1.5		"F	
	per transceiver (A to B: outputs disabled)	$t_{rise} = t_{fall} = 1 \text{ ns}$	1.5 V	1.5 V		1.5		pF
	,	Tion idii	1.8 V	1.8 V		1.5		
			2.5 V	2.5 V		1.6		
			3.3 V	3.3 V		2.0		
pdA			0.7 V	0.7 V		2.2 2.4 3.0 1.5 1.5 1.5 1.5 1.5 1.6 2.0 13.4 15.0 14.0 20.7 29.6 40.2 65.8 91.7 1.3 1.1		
			0.8 V	0.8 V				
			0.9 V	0.9 V		14.0		
	Power Dissipation Capacitance	$C_L = 0$, $R_L = Open$	1.2 V	1.2 V		20.7		
	per transceiver (B to A: outputs enabled)	f = 1 MHz t _{rise} = t _{fall} = 1 ns	1.5 V	1.5 V		29.6		pF
	,	nac iaii	1.8 V	1.8 V		40.2		
			2.5 V	2.5 V		65.8		
			3.3 V	3.3 V		91.7		
			0.7 V	0.7 V		1.3		
			0.8 V	0.8 V		1.1		
			0.9 V	0.9 V		1.1		
	Power Dissipation Capacitance	$C_L = 0$, $R_L = Open$	1.2 V	1.2 V		1.0		_
	per transceiver (B to A: outputs disabled)	f = 1 MHz t _{rise} = t _{fall} = 1 ns	1.5 V	1.5 V		1.0		pF
	,	noc idii	1.8 V	1.8 V		1.0		
			2.5 V	2.5 V		1.0		
			3.3 V	3.3 V		1.0		

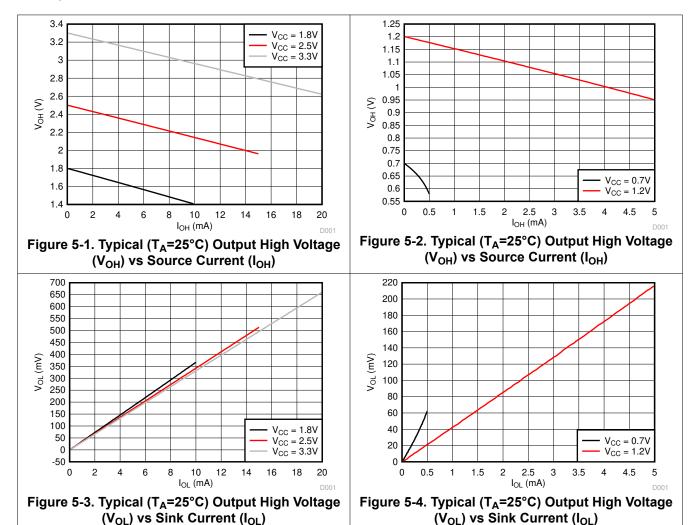


5.14 Operating Characteristics: T_A = 25°C (continued)

	PARAMETER	TEST CONDITIONS	V _{CCA}	V _{CCB}	MIN	TYP	MAX	UNIT
			0.7 V	0.7 V		13.4		
			0.8 V	0.8 V		13.8		
			0.9 V	0.9 V		14.9		
	Power Dissipation Capacitance	$C_L = 0$, $R_L = Open$	1.2 V	1.2 V		20.6		
	per transceiver (A to B: outputs enabled)	f = 1 MHz t _{rise} = t _{fall} = 1 ns	1.5 V	1.5 V		29.6		pF
	,	noc iai	1.8 V	1.8 V		40.3		
			2.5 V	2.5 V		66.2		
			3.3 V	3.3 V		92.5		
			0.7 V	0.7 V		1.3		
			0.8 V	0.8 V		1.2		
			0.9 V	0.9 V		1.1		
	Power Dissipation Capacitance	$C_L = 0$, $R_L = Open$	1.2 V	1.2 V		1.1		"F
	per transceiver (A to B: outputs disabled)	f = 1 MHz $t_{\text{rise}} = t_{\text{fall}} = 1 \text{ ns}$	1.5 V	1.5 V		1.1		pF
		, indicate the second s	1.8 V	1.8 V		1.1		
			2.5 V	2.5 V		1.1		
			3.3 V	3.3 V		1.1		
pdB			0.7 V	0.7 V		2.5	13.4 13.8 14.9 20.6 29.6 40.3 66.2 92.5 1.3 1.2 1.1 1.1 1.1 1.1	
			0.8 V	0.8 V		2.4		
			0.9 V	0.9 V		2.3		
	Power Dissipation Capacitance	$C_L = 0$, $R_L = Open$	1.2 V	1.2 V		2.2		
	per transceiver (B to A: outputs enabled)	f = 1 MHz t _{rise} = t _{fall} = 1 ns	1.5 V	1.5 V		2.3		pF
	,	noc iai	1.8 V	1.8 V		2.3		
			2.5 V	2.5 V		2.5		
			3.3 V	3.3 V		3.0		
			0.7 V	0.7 V		1.6		
			0.8 V	0.8 V		1.5		
			0.9 V	0.9 V		1.5		
	Power Dissipation Capacitance	$C_L = 0$, $R_L = Open$	1.2 V	1.2 V		1.5		, r
	per transceiver (B to A: outputs disabled)	f = 1 MHz t _{rise} = t _{fall} = 1 ns	1.5 V	1.5 V		1.5		pF
			1.8 V	1.8 V		1.5		
			2.5 V	2.5 V		1.6		
			3.3 V	3.3 V		2.0		



5.15 Typical Characteristics



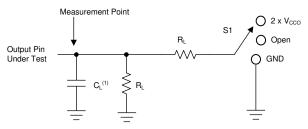


6 Parameter Measurement Information

6.1 Load Circuit and Voltage Waveforms

Unless otherwise noted, all input pulses are supplied by generators having the following characteristics:

- f = 1 MHz
- $Z_{O} = 50 \Omega$
- dv/dt ≤ 1 ns/V

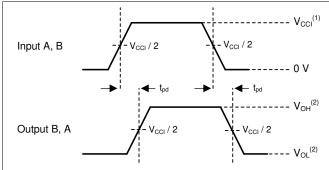


A. C_L includes probe and jig capacitance.

Figure 6-1. Load Circuit

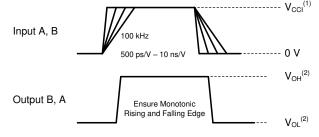
Table 6-1. Load Circuit Conditions

	Parameter	V _{cco}	R_L	CL	S ₁	V _{TP}
Δt/Δν	Input transition rise or fall rate	0.65 V – 3.6 V	1 ΜΩ	15 pF	Open	N/A
		1.1 V – 3.6 V	2 kΩ	15 pF	Open	N/A
t _{pd}	Propagation (delay) time	0.65 V - 0.95 V	20 kΩ	15 pF	Open	N/A
		3 V – 3.6 V	2 kΩ	15 pF	2 × V _{CCO}	0.3 V
		1.65 V – 2.7 V	2 kΩ	15 pF	2 × V _{CCO}	0.15 V
t _{en} , t _{dis}	Enable time, disable time	1.1 V – 1.6 V	2 kΩ	15 pF	2 × V _{CCO}	0.1 V
		0.65 V - 0.95 V	20 kΩ	15 pF	2 × V _{CCO}	0.1 V
		3 V – 3.6 V	2 kΩ	15 pF	GND	0.3 V
		1.65 V – 2.7 V	2 kΩ	15 pF	GND	0.15 V
t _{en} , t _{dis}	Enable time, disable time	1.1 V – 1.6 V	2 kΩ	15 pF	GND	0.1 V
		0.65 V – 0.95 V	20 kΩ	15 pF	GND	0.1 V



- 1. V_{CCI} is the supply pin associated with the input port.
- 2. V_{OH} and V_{OL} are typical output voltage levels that occur with specified R_L , C_L , and S_1

Figure 6-2. Propagation Delay



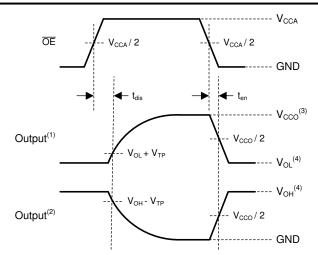
- 1. V_{CCI} is the supply pin associated with the input port.
- 2. V_{OH} and V_{OL} are typical output voltage levels that occur with specified R_L , C_L , and S_1

Figure 6-3. Input Transition Rise or Fall Rate

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- A. Output waveform on the condition that input is driven to a valid Logic Low.
- B. Output waveform on the condition that input is driven to a valid Logic High.
- C. V_{CCO} is the supply pin associated with the output port.
- D. $\;\;$ V_{OH} and V_{OL} are typical output voltage levels with specified R_L, C_L, and S₁.

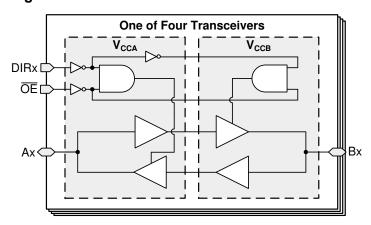
Figure 6-4. Enable Time And Disable Time

7 Detailed Description

7.1 Overview

The SN74AXC4T774 is a 4-bit, dual-supply noninverting bidirectional voltage level translation device. Ax pins and control pins (DIRx and $\overline{\text{OE}}$) are reference to V_{CCA} logic levels, and Bx pins are referenced to V_{CCB} logic levels. The A port is able to accept I/O voltages ranging from 0.65 V to 3.6 V, while the B port can accept I/O voltages from 0.65 V to 3.6 V. A high on DIR allows data transmission from A to B and a low on DIR allows data transmission from B to A when \overline{OE} is set to low. When \overline{OE} is set to high, both Ax and Bx pins are in the high-impedance state. See Device Functional Modes for a summary of the operation of the control logic.

7.2 Functional Block Diagram



7.3 Feature Description

7.3.1 Standard CMOS Inputs

Standard CMOS inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the Electrical Characteristics. The worst case resistance is calculated with the maximum input voltage, given in the Absolute Maximum Ratings, and the maximum input leakage current, given in the *Electrical Characteristics*, using ohm's law (R = V ÷ I).

Signals applied to the inputs need to have fast edge rates, as defined by Δt/Δv in Recommended Operating Conditions to avoid excessive current consumption and oscillations. If a slow or noisy input signal is required, a device with a Schmitt-trigger input should be used to condition the input signal prior to the standard CMOS input.

7.3.2 Balanced High-Drive CMOS Push-Pull Outputs

A balanced output allows the device to sink and source similar currents. The high drive capability of this device creates fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. The electrical and thermal limits defined in the Absolute Maximum Ratings must be followed at all times.

7.3.3 Partial Power Down (I_{off})

The inputs and outputs for this device enter a high-impedance state when the device is powered down, inhibiting current backflow into the device. The maximum leakage into or out of any input or output pin on the device is specified by I_{off} in the Electrical Characteristics.

7.3.4 V_{CC} Isolation

The inputs and outputs for this device enter a high-impedance state when either supply is <100mV.

7.3.5 Over-voltage Tolerant Inputs

Input signals to this device can be driven above the supply voltage so long as they remain below the maximum input voltage value specified in the Recommended Operating Conditions.

7.3.6 Glitch-Free Power Supply Sequencing

Either supply rail may be powered on or off in any order without producing a glitch on the I/Os (that is, where the output erroneously transitions to VCC when it should be held low). Glitches of this nature can be misinterpreted by a peripheral as a valid data bit, which could trigger a false device reset of the peripheral, a false device configuration of the peripheral, or even a false data initialization by the peripheral. For more information regarding the power up glitch performance of the AXC family of level translators, see the *Glitch Free Power Sequencing With AXC Level Translators* application report

7.3.7 Negative Clamping Diodes

The inputs and outputs to this device have negative clamping diodes as depicted in Figure 7-1.

CAUTION

Voltages beyond the values specified in the Absolute Maximum Ratings table can cause damage to the device. The input negative-voltage and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

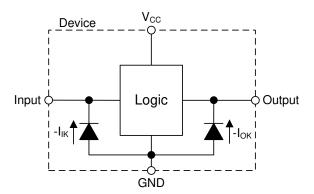


Figure 7-1. Electrical Placement of Clamping Diodes for Each Input and Output

7.3.8 Fully Configurable Dual-Rail Design

Both the V_{CCA} and V_{CCB} pins can be supplied at any voltage from 0.65 V to 3.6 V, making the device suitable for translating between any of the voltage nodes (0.7 V, 0.8 V, 0.9 V, 1.2 V, 1.8 V, 2.5 V and 3.3 V).

7.3.9 I/Os with Integrated Static Pull-Down Resistors

To help avoid floating inputs on the I/Os, this device has $71k\Omega$ typical integrated weak pull-downs on all data I/Os. This feature allows all inputs to be left floating without the concern for unstable outputs or increased current consumption. This also helps to reduce external component count for applications where not all channels are used or need to be fixed low. If an external pull-up is required, it should be no larger than $7k\Omega$ to avoid contention with the $71k\Omega$ internal pull-down.

7.3.10 Supports High-Speed Translation

The SN74AXC4T774 device can support high data-rate applications. The translated signal data rate can be up to 310 Mbps when the signal is translated from 1.8 V to 3.3 V.

7.4 Device Functional Modes

Table 7-1. Function Table (Each Transceiver)

	(Eddit Hallocolver)													
CONTROL	INPUTS ⁽¹⁾ (2)	PORT S	TATUS	OPERATION										
ŌĒ	DIR	A PORT	B PORT	OFERATION										
L	L	Output (Enabled)	Input (Hi-Z)	B data to A bus										
L	Н	Input (Hi-Z)	Output (Enabled)	A data to B bus										

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Table 7-1. Function Table (Each Transceiver) (continued)

CONTROL	INPUTS ⁽¹⁾ (2)	PORT S	TATUS	OPERATION
ŌĒ	DIR	A PORT	B PORT	OPERATION
Н	X	Input (Hi-Z)	Input (Hi-Z)	Isolation

- Input circuits of the data I/Os are always active.
- Pins configured as inputs should not be left floating.

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8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The SN74AXC4T774 device can be used in level-translation applications for interfacing devices or systems operating at different interface voltages with one another. The SN74AXC4T774 device is ideal for use in applications where a push-pull driver is connected to the data I/Os. The max data rate can be up to 310 Mbps when device translates a signal from 1.8 V to 3.3 V.

One example application is shown in Figure 8-1, where the SN74AXC4T774 device is used to translate a low voltage SPI signal from an SoC to a higher voltage signal to properly drive the inputs of a GPS module, and vice versa.

8.2 Typical Application

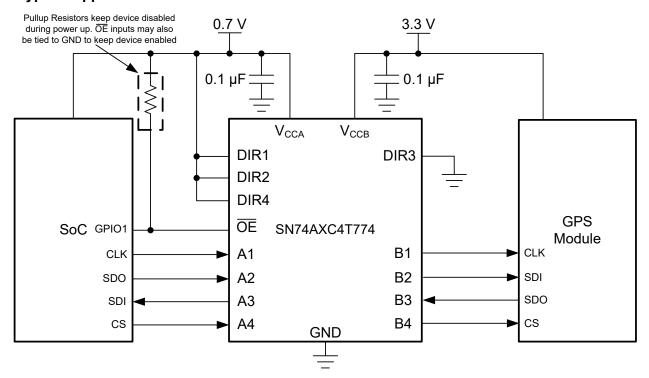


Figure 8-1. Serial Peripheral Interface (SPI) Application

8.2.1 Design Requirements

For this design example, use the parameters listed in Table 8-1.

Table 8-1. Design Parameters

	<u> </u>
DESIGN PARAMETERS	EXAMPLE VALUES
Input voltage range	0.65 V to 3.6 V
Output voltage range	0.65 V to 3.6 V



8.2.2 Detailed Design Procedure

To begin the design process, determine the following:

- Input voltage range
 - Use the supply voltage of the device that is driving the SN74AXC4T774 device to determine the input voltage range. For a valid logic-high, the value must exceed the high-level input voltage (V_{IH}) of the input port. For a valid logic low the value must be less than the low-level input voltage (V_{\parallel}) of the input port.
- Output voltage range
 - Use the supply voltage of the device that the SN74AXC4T774 device is driving to determine the output voltage range.

8.2.3 Application Curve



Figure 8-2. Up Translation at 2.5 MHz (0.7 V to 3.3 V)

8.3 Power Supply Recommendations

Always apply a ground reference to the GND pins first. This device is designed for glitch free power sequencing without any supply sequencing requirements such as ramp order or ramp rate.

This device was designed with various power supply sequencing methods in mind to help prevent unintended triggering of downstream devices. For more information regarding the power up glitch performance of the AXC family of level translators, see the Glitch Free Power Sequencing With AXC Level Translators application report



8.4 Layout

8.4.1 Layout Guidelines

For device reliability, following common printed-circuit board layout guidelines are recommended:

- Use bypass capacitors on the power supply pins and place them as close to the device as possible. A
 0.1μF capacitor is recommended, but transient performance can be improved by having both 1μF and 0.1μF
 capacitors in parallel as bypass capacitors.
- The high drive capability of this device creates fast edges into light loads so routing and load conditions should be considered to prevent ringing.

8.4.2 Layout Example

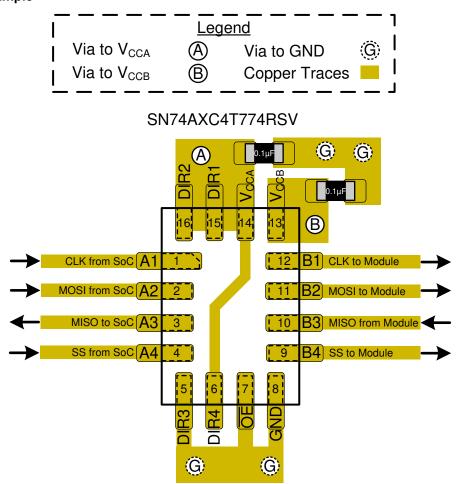


Figure 8-3. Layout Example



9 Device and Documentation Support

9.1 Documentation Support

9.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, Implications of Slow or Floating CMOS Inputs application report
- Texas Instruments, Power Sequencing for AXC Family of Devices application report
- Texas Instruments, SN74AXC4T774 Evaluation Module Tool Folder

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on Notifications to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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9.4 Trademarks

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9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

Changes from Revision B (May 2021) to Revision C (May 2022)	Page
Added the I/Os with Integrated Static Pull-Down Resistors section	20
Changes from Revision A (July 2020) to Revision B (May 2021)	Page
Updated the Serial Peripheral Interface (SPI) Application figure in the Typical Application section	23
Changes from Revision * (July 2019) to Revision A (July 2020)	Page
 Updated the numbering format for tables, figures and cross-references throughout the document Added BQB (WQFN) package option to <i>Device Information</i> table 	



11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com 20-Jan-2024

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN74AXC4T774BQBR	ACTIVE	WQFN	BQB	16	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	4T774	Samples
SN74AXC4T774PWR	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SN4T774	Samples
SN74AXC4T774RSVR	ACTIVE	UQFN	RSV	16	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1UXR	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN74AXC4T774:

Automotive : SN74AXC4T774-Q1

NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

PACKAGE MATERIALS INFORMATION

www.ti.com 7-Oct-2023

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AXC4T774BQBR	WQFN	BQB	16	3000	180.0	12.4	2.8	3.8	1.2	4.0	12.0	Q1
SN74AXC4T774PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AXC4T774RSVR	UQFN	RSV	16	3000	178.0	13.5	2.1	2.9	0.75	4.0	12.0	Q1

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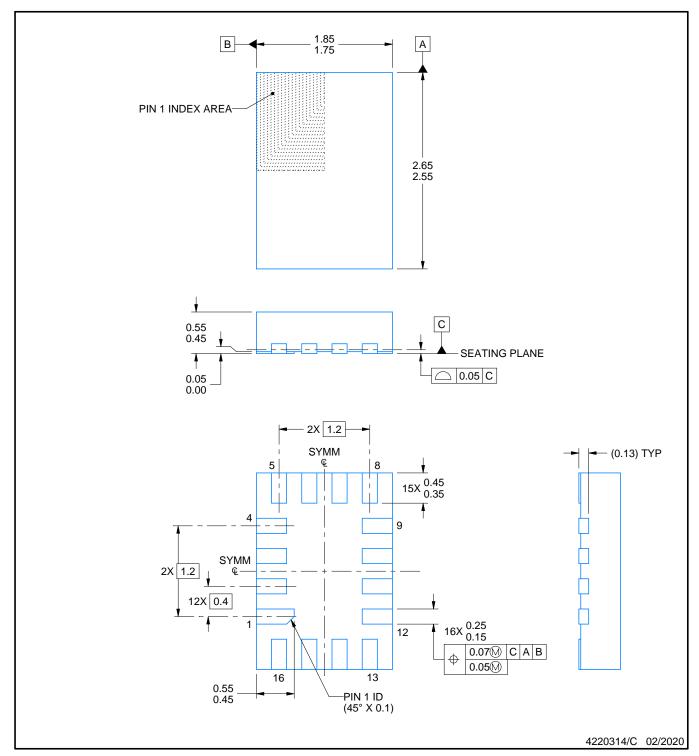


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AXC4T774BQBR	WQFN	BQB	16	3000	210.0	185.0	35.0
SN74AXC4T774PWR	TSSOP	PW	16	2000	356.0	356.0	35.0
SN74AXC4T774RSVR	UQFN	RSV	16	3000	189.0	185.0	36.0



ULTRA THIN QUAD FLATPACK - NO LEAD

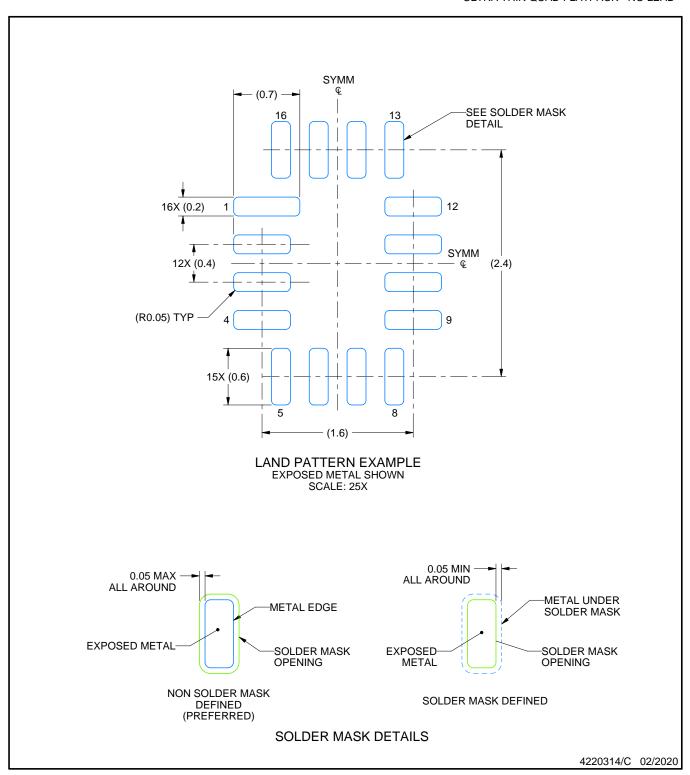


NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 This drawing is subject to change without notice.



ULTRA THIN QUAD FLATPACK - NO LEAD

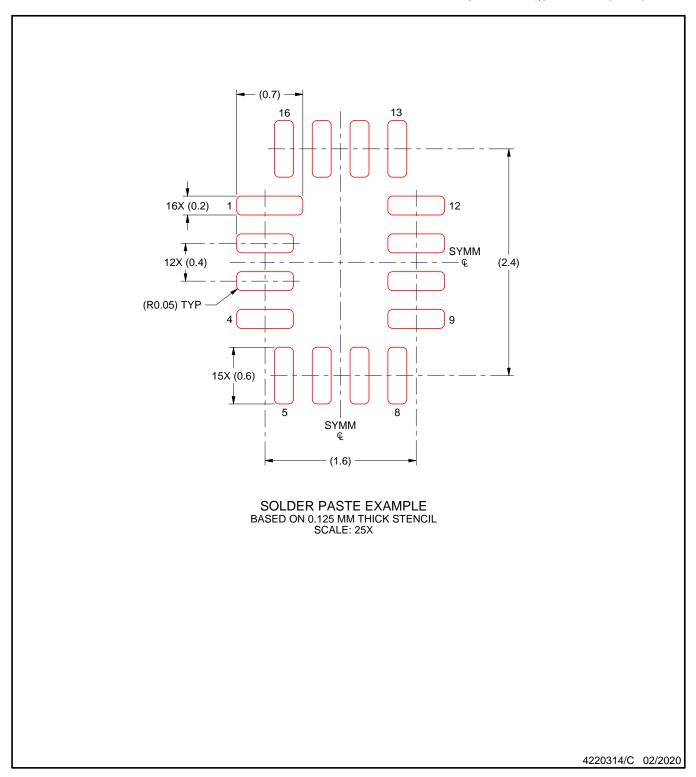


NOTES: (continued)

3. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).



ULTRA THIN QUAD FLATPACK - NO LEAD



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



2.5 x 3.5, 0.5 mm pitch

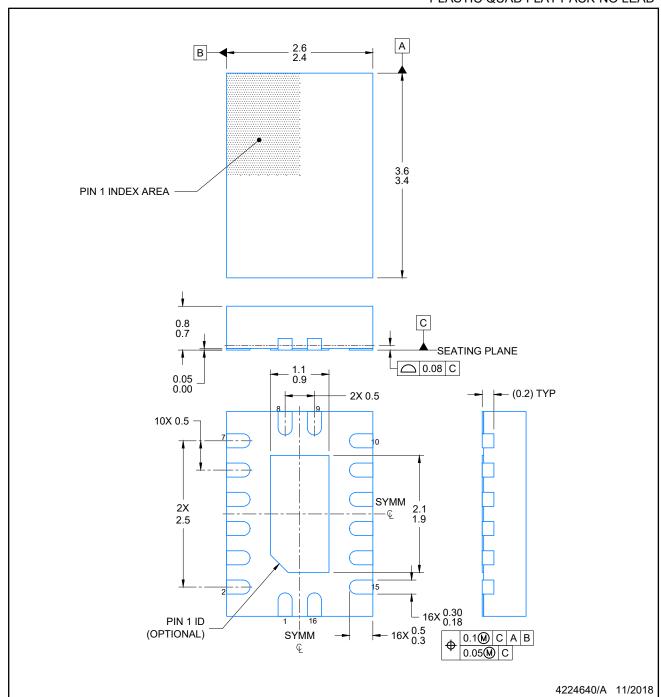
PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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PLASTIC QUAD FLAT PACK-NO LEAD

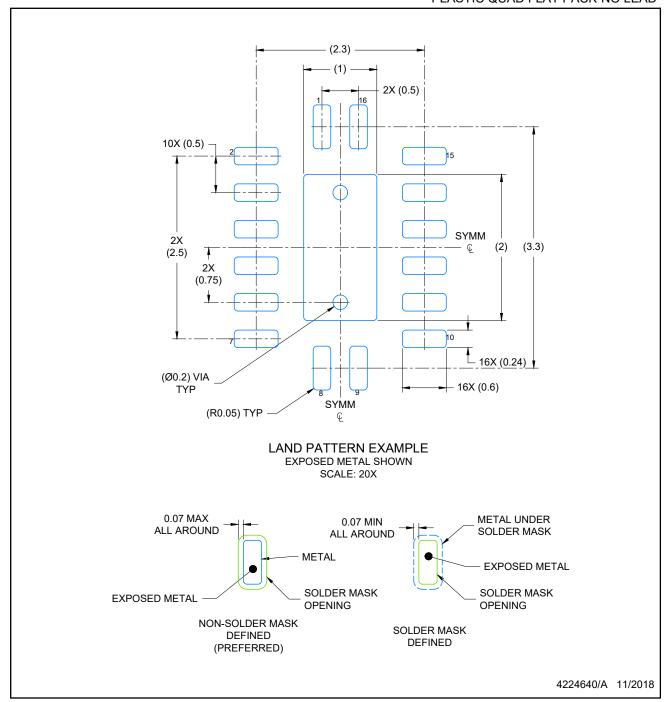


NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



PLASTIC QUAD FLAT PACK-NO LEAD

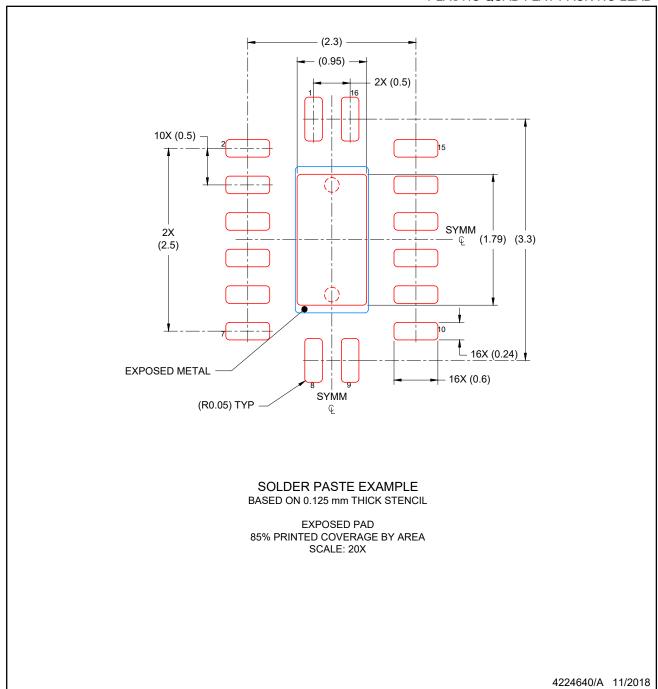


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLAT PACK-NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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